


<b>Search Notes</b>  	<b>Application/Control No.</b>  10584043	<b>Applicant(s)/Patent Under Reexamination</b>  ALLIOT ET AL.
	<b>Examiner</b>  SHEELA C CHAWAN	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	232, 233, 305,100	9/13/09	SCC
375	326,347,340,E1.002,332,343,141,341,342,147,324,327,344,323,298,260,148,150,152,271,316.	"	"
370	335,208,342,491,441,204,215,320,345	9/13/09	SCC
455	101,502,69,522,562.1,255,135,67,11,442	9/13/09	SCC
382	232	6/30/10	SCC
370	204	6/30/10	SCC
375	147	6/30/10	SCC
455	67.11	6/30/10	SCC
SEARCH UP-DATE		6/30/10	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY.	9/13/09	SCC
SEARCH INVENTOR NAME	9/13/09	SCC
SEARCH EAST AND OTHER DATA BASE , SEE THE SEARCH HISTORY .	6/30/10	SCC
382/232,233,305,100.CCLS.	6/30/10	SCC
375/326,347,340,E1.002,332,343,141,341,342,147,324,327,344,323,298,260,148,150,152,271,316.CCLS.	6/30/10	SCC
370/335,208,342,491,441.CCLS.	6/30/10	SCC
455/101,502,69,522,562.1,255,135,67,11,442.CCLS.	6/30/10	SCC
INTERFERENCE SEARCH	6/30/10	SCC
SEARCH IEEE OR INSPEC DATA BASE.	6/30/10	SCC
SEARCH UP-DATA	6/30/10	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	232	6/30/10	SCC
370	204	6/30/10	SCC
375	147	6/30/10	SCC
455	67.11	6/30/10	SCC

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